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TITLE: Circuit board inspection apparatus performs quality test of circuit board based on measured electrostatic capacitance between the probes provided in probe holders

PATENT-ASSIGNEE:

ASSIGNEE

HIOKI DENKI KK

CODE

HIOKN

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ABSTRACTED-PUB-NO: JP2000206170A

BASIC-ABSTRACT:

NOVELTY - Several probes (12) are provided in probe holder (11) arranged at one side surface (Pa) of circuit board (P). Conductor patterns are arranged to other side surface (Pb) of board. Several contact type probes (16) are provided in probe holder (15) such that they contact the patterns. The electrostatic capacitance between probes (12,16) is measured, based on which quality test of circuit board is performed.

USE - For inspecting quality of circuit board.

ADVANTAGE - Performs quality test of circuit board, based on measured electrostatic capacitance. The conductor insulation of each conductor pattern is performed with high precision, in short time.

DESCRIPTION OF DRAWING(S) - The figure shows the sectional view of component of circuit board inspection apparatus.

Probe holders 11,15

Probes 12,16

Circuit board P

Surfaces of circuit boards Pa,Pb

CHOSEN-DRAWING: Dwg.4/16

TITLE-TERMS: CIRCUIT BOARD INSPECT APPARATUS PERFORMANCE QUALITY TEST CIRCUIT BOARD
BASED MEASURE ELECTROSTATIC CAPACITANCE PROBE PROBE HOLD

DERWENT-CLASS: S01

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SECONDARY-ACC-NO:

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